Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/803,999	TAKAHASHI ET AL.	
Examiner	**Art Unit**	
Sin J. Lee	1752	

SEARCHED

Class	Subclass	Date	Examiner
430	271.1	5-29-05	SJL
	278.1		
	270.1		
	944		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Structure search for formula (I) of cl. #2	11-7-05	SJL
Structure search for formula (I-b) of cl. #5		